







SN74AXC2T45-Q1

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SN74AXC2T45-Q1 Automotive 2-Bit Translating Transceiver with Configurable Level-**Shifting**

1 Features

- AEC-Q100 automotive qualified
- Fully configurable dual-rail design allows each port to operate with a power supply range from 0.65V to 3.6V
- Operating temperature from -40°C to +125°C
- Glitch-free power supply sequencing
- Up to 380Mbps support when translating from 1.8V to 3.3V
- V_{CC} isolation feature
 - If either V_{CC} input is below 100mV, all I/Os outputs are disabled and become highimpedance
- Ioff supports partial-power-down mode operation
- Compatible with AVC family level shifters
- Latch-up performance exceeds 100mA per JESD 78. Class II
- ESD protection exceeds JESD 22
 - 8000-V human-body model
 - 1000-V charged-device model

2 Applications

- Enterprise and communications
- Industrial
- Personal electronics
- Wireless infrastructure
- **Building automation**
- Point-of-sale

3 Description

The SN74AXC2T45-Q1 is a two-bit noninverting bus transceiver that uses two individually configurable power-supply rails. The device is operational with both V_{CCA} and V_{CCB} supplies as low as 0.65V. The A port is designed to track V_{CCA}, which accepts any supply voltage from 0.65V to 3.6V. The B port is designed to track V_{CCB}, which also accepts any supply voltage from 0.65V to 3.6V. Additionally the SN74AXC2T45-Q1 is compatible with a single-supply system.

The SN74AXC2T45-Q1 device is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level of the direction-control input (DIR). The SN74AXC2T45-Q1 device is designed so the control pin (DIR) is referenced to V_{CCA}.

This device is fully specified for partial-power-down applications using the I_{off} current. The I_{off} protection circuitry is designed so that no excessive current is drawn from or to an input, output, or combined I/O that is biased to a specific voltage while the device is powered down.

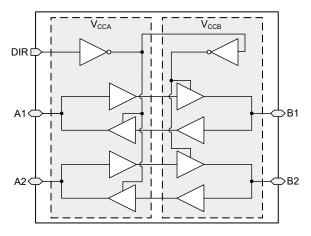
The V_{CC} isolation feature is designed so that if either V_{CCA} or V_{CCB} is less than 100mV, both I/O ports enter a high-impedance state by disabling their outputs.

Glitch-free power supply sequencing allows either supply rail to be powered on or off in any order while providing robust power sequencing performance.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
SN74AXC2T45-Q1	DCU (VSSOP, 8)	2mm × 3.1mm

- (1)For more information, see Section 10.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Functional Block Diagram



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4 Pin Configuration and Functions

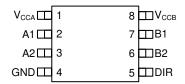


Figure 4-1. DCU Package, 8-Pin VSSOP (Top View)

Table 4-1. Pin Functions

	PIN	TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.	IIPE\/	DESCRIPTION
A1	2	I/O	Input/output A1. Referenced to V _{CCA} .
A2	3	I/O	Input/output A2. Referenced to V _{CCA} .
B1	7	I/O	Input/output B1. Referenced to V _{CCB} .
B2	6 1/		Input/output B2. Referenced to V _{CCB} .
DIR	5		Direction-control in for both ports. Referenced to V _{CCA}
GND	4	G	Ground
V _{CCA}	1	Р	A-port power supply voltage. 0.65V ≤ V _{CCA} ≤ 3.6V
V _{CCB}	8	Р	B-port power supply voltage. 0.65V ≤ V _{CCB} ≤ 3.6V

(1) I = input, O = output, P = power, G = ground



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNITS
V_{CCA}	Supply voltage A		-0.5	4.2	V
V_{CCB}	Supply voltage B		-0.5	4.2	V
		I/O Ports (A Port)	-0.5	4.2	
V_{I}	Input Voltage ⁽²⁾	I/O Ports (B Port)	-0.5	4.2	V
		Control Inputs	-0.5	4.2	
	Value and the day of the trial to the birth in the birth	A Port	-0.5	4.2	.,
Vo	Voltage applied to any output in the high-impedance or power-off state ⁽²⁾	B Port	-0.5	4.2	V
\ /	Valle as a multi-old to a more status to the bright and law state (2) (3)	A Port	-0.5	V _{CCA} + 0.2	V
Vo	Voltage applied to any output in the high or low state ^{(2) (3)}	B Port	-0.5	V _{CCB} + 0.2	, v
I _{IK}	Input clamp current	V _I < 0	-50		mA
I _{OK}	Output clamp current	V _O < 0	-50		mA
Io	Continuous output current		-50	50	mA
	Continuous current through V _{CC} or GND		-100	100	mA
Tj	Junction Temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input voltage and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The output positive-voltage rating may be exceeded up to 4.2V maximum if the output current rating is observed.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±8000	V
V _(ESD)	Liectiostatic discharge	Charged device model (CDM), per AEC Q100-011	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.



5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1) 2

				MIN	MAX	UNIT
V _{CCA}	Supply voltage A			0.65	3.6	V
V _{CCB}	Supply voltage B			0.65	3.6	V
			$V_{CCI} = 0.65V - 0.75V$	V _{CCI} × 0.70		
			V _{CCI} = 0.76V - 1V	V _{CCI} × 0.70		
		Data Inputs	V _{CCI} = 1.1V – 1.95V	V _{CCI} × 0.65		
			V _{CCI} = 2.3V – 2.7V	1.6		
.,	I Park Land Samuel and Research		V _{CCI} = 3V – 3.6V	2		
V_{IH}	High-level input voltage		V _{CCA} = 0.65V - 0.75V	V _{CCA} × 0.70		
			V _{CCA} = 0.76V – 1V	V _{CCA} × 0.70		
		Control Input (DIR), Referenced to V _{CCA}	V _{CCA} = 1.1V – 1.95V	V _{CCA} × 0.65		
		IO A CCA	V _{CCA} = 2.3V – 2.7V	1.6		
			V _{CCA} = 3V – 3.6V	2		
			$V_{CCI} = 0.65V - 0.75V$		V _{CCI} x 0.30	
			V _{CCI} = 0.76V – 1V		V _{CCI} x 0.30	
		Data Inputs	V _{CCI} = 1.1V – 1.95V		V _{CCI} x 0.35	
			V _{CCI} = 2.3V – 2.7V		0.7	
V	Low lovel input veltage		V _{CCI} = 3V – 3.6V		0.8	V
V_{IL}	Low-level input voltage		$V_{CCA} = 0.65V - 0.75V$		V _{CCA} × 0.30	V
			V _{CCA} = 0.76V – 1V		V _{CCA} × 0.30	
		Control Input (DIR), Referenced to V _{CCA}	V _{CCA} = 1.1V – 1.95V		V _{CCA} × 0.35	
		LO VOCA	V _{CCA} = 2.3V – 2.7V		0.7	
			V _{CCA} = 3V – 3.6V		0.8	
V _I	Input voltage			0	3.6	V
V	Output voltage	Active State		0	V _{CCO}	V
Vo	Output voltage	Tri-State		0	3.6	V
Δt/Δv ²	Input transition rise and	fall time			10	ns/V
Δt/Δv ³	Single channel input tran	nsition rise and fall time			100	ns/V
T _A	Operating free-air tempe	rature		-40	125	°C

⁽¹⁾

5.4 Thermal Information

	TUEDNAL METDIO (1)	:	SN74AXC2T45-Q	1	
	THERMAL METRIC (1)	DCT (SM8)	DCU (VSSOP)	DTM (X2SON)	UNIT
R _{θJA}	Junction-to-ambient thermal resistance	223.5	242.9	225.9	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	120.7	96.2	131.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	138.0	153.3	141.3	°C/W
Y _{JT}	Junction-to-top characterization parameter	47.5	38.2	12.7	°C/W
Y _{JB}	Junction-to-board characterization parameter	136.7	152.5	140.9	°C/W

(1) For more information about thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

Product Folder Links: SN74AXC2T45-Q1

 V_{CCI} is the V_{CC} associated with the input port. V_{CCO} is the V_{CC} associated with the output port. All unused inputs of the device must be held at V_{CC} or GND for proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.

Input transition rate of a single channel while the other channels are at a valid logic state and not switching.



5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted) (1) (2) (3)

						Оре	erating free-a	ir temper	ature (T _A)	
PA	RAMETER	TEST	CONDITIONS	V _{CCA}	V _{CCB}	-40°	C to 85°C	-40°	C to 125°	,C	UNIT
						MIN	TYP MA	X MIN	TYP	MAX	
			I _{OH} = -100μA	0.7V - 3.6V	0.7V - 3.6V	V _{CCO} -0.1		V _{CCO} -0.1			
			I _{OH} = -50μA	0.65V	0.65V	0.55		0.55			
			I _{OH} = -200μA	0.76V	0.76V	0.58		0.58			
	High-level		I _{OH} = -500μA	0.85V	0.85V	0.65		0.65			
/ _{OH}	output voltage	$V_I = V_{IH}$	I _{OH} = -3mA	1.1V	1.1V	0.85		0.85			V
			I _{OH} = -6mA	1.4V	1.4V	1.05		1.05			
			I _{OH} = -8mA	1.65V	1.65V	1.2		1.2			
			I _{OH} = -9mA	2.3V	2.3V	1.75		1.75			
			I _{OH} = -12mA	3V	3V	2.3		2.3			
			I _{OL} = 100μA	0.7V - 3.6V	0.7V - 3.6V		0.	1		0.1	
			I _{OL} = 50μA	0.65V	0.65V		0.	1		0.1	
			I _{OL} = 200μA	0.76V	0.76V		0.1	8		0.18	
			I _{OL} = 500μA	0.85V	0.85V		0.	2		0.2	
/ _{OL}	Low-level output voltage	V _I = V _{IL}	I _{OL} = 3mA	1.1V	1.1V		0.2	5		0.25	V
	surput tellings		I _{OL} = 6mA	1.4V	1.4V		0.3	5		0.35	
			I _{OL} = 8mA	1.65V	1.65V		0.4	5		0.45	
			I _{OL} = 9mA	2.3V	2.3V		0.5	5		0.55	
			I _{OL} = 12mA	3V	3V		0.	7		0.7	
	Input leakage	Control in V _{CCA} or 0	nput (DIR):V _I = GND	0.65V - 3.6V	0.65V - 3.6V	-0.5	0.	5 -1		1	μΑ
1	current	Data Inpo	uts (Ax, Bx),V _I = GND	0.65V - 3.6V	0.65V - 3.6V	-4		4 -8		8	μA
off	Partial power	A Port: V 3.6V	I_1 or $V_0 = 0V -$	0V	0V - 3.6V	-4		4 -8		8	μA
οπ	down current	B Port: V 3.6V	or V _O = 0V –	0V – 3.6V	0V	-4		4 -8		8	μ,
	V gunnhy	V ₁ =		0.65V - 3.6V	0.65V - 3.6V			8		14	
CCA	V _{CCA} supply current	V _{CCI} or	I _O = 0	0V	3.6V	-2		-12			μΑ
		GND		3.6V	0V			4		8	
	V aummh	V ₁ =		0.65V - 3.6V	0.65V - 3.6V			8		14	
ССВ	V _{CCB} supply current	V _{CCI} or	I _O = 0	0V	3.6V			4		8	μΑ
		GND		3.6V	0V	-2		-12			
CCA +	Combined supply current	V _I = V _{CCI} or GND	I _O = 0	0.65V - 3.6V	0.65V - 3.6V		1	6		23	μA
Ç _i	Control Input (DIR) Capacitance	V _I = 3.3V	or GND	3.3V	3.3V		3.3		3.3		pF
S _{io}	Data I/O Capacitance		5V DC +1MHz sine wave	3.3V	3.3V		5.4		5.4		pF

 V_{CCI} is the V_{CC} associated with the input port. V_{CCO} is the V_{CC} associated with the output port. All typical data is taken at 25°C. (1) (2)



5.6 Switching Characteristics, $V_{CCA} = 0.7 \pm 0.05V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})								
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ± ().2V	3.3 ±	0.3V	UNIT	
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
		_	В	-40°C to 85°C	0.5	170	0.5	115	0.5	84	0.5	50	0.5	50	0.5	56	0.5	71	0.5	106		
	Propagation	A	В	-40°C to 125°C	0.5	170	0.5	115	0.5	84	0.5	50	0.5	50	0.5	56	0.5	71	0.5	106	ns	
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	170	0.5	149	0.5	122	0.5	83	0.5	79	0.5	78	0.5	77	0.5	76		
		B	A	-40°C to 125°C	0.5	170	0.5	149	0.5	122	0.5	83	0.5	79	0.5	78	0.5	77	0.5	76		
		DIR	Α	-40°C to 85°C	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140		
	Disable time	DIK	A	-40°C to 125°C	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140		
t _{dis}	Disable time	DIR	В	-40°C to 85°C	0.5	143	0.5	105	0.5	84	0.5	41	0.5	39	0.5	42	0.5	56	0.5	107	ns	
		DIK		-40°C to 125°C	0.5	143	0.5	105	0.5	84	0.5	41	0.5	39	0.5	42	0.5	56	0.5	107		
		DIR	Α	-40°C to 85°C	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311		
	Enable time	DIK	A	-40°C to 125°C	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	no	
t _{en}	Eliable tille	DID	DIR	В	-40°C to 85°C	0.5	306	0.5	247	0.5	216	0.5	186	0.5	182	0.5	183	0.5	194	0.5	228	ns
		אוטו	D	-40°C to 125°C	0.5	306	0.5	247	0.5	216	0.5	186	0.5	182	0.5	183	0.5	194	0.5	228		

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5.7 Switching Characteristics, $V_{CCA} = 0.8 \pm 0.04V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})							
t _{pd} d	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	150	0.5	94	0.5	63	0.5	33	0.5	28	0.5	27	0.5	28	0.5	34	
	Propagation			-40°C to 125°C	0.5	150	0.5	94	0.5	63	0.5	33	0.5	28	0.5	27	0.5	28	0.5	34	ns
^L pd	delay	В	Α	-40°C to 85°C	0.5	115	0.5	94	0.5	76	0.5	50	0.5	41	0.5	40	0.5	38	0.5	38	115
			^	-40°C to 125°C	0.5	115	0.5	94	0.5	76	0.5	50	0.5	41	0.5	40	0.5	38	0.5	38	
		DIR	Α	-40°C to 85°C	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	
.	Disable time	DIK	^	-40°C to 125°C	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	ne
t _{dis}	Disable time	DIR	В	-40°C to 85°C	0.5	136	0.5	97	0.5	76	0.5	33	0.5	27	0.5	26	0.5	28	0.5	35	ns
		DIIX	Ь	-40°C to 125°C	0.5	136	0.5	97	0.5	76	0.5	33	0.5	27	0.5	26	0.5	28	0.5	35	
		DIR	Α	-40°C to 85°C	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	
t _{en}	Enable time	DIK	A	-40°C to 125°C	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	, no
(1)	Litable title	DIR	В	-40°C to 85°C	0.5	243	0.5	188	0.5	157	0.5	128	0.5	123	0.5	122	0.5	123	0.5	125	ns
		DIIX	D	-40°C to 125°C	0.5	243	0.5	188	0.5	157	0.5	128	0.5	123	0.5	122	0.5	123	0.5	125	

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.8 Switching Characteristics, $V_{CCA} = 0.9 \pm 0.045V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

											B-Port S	Supply '	Voltage	(V _{CCB})							
P	PARAMETER FF t _{pd} Propagation delay B t _{dis} Disable time DIR	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		_	В	-40°C to 85°C	0.5	122	0.5	76	0.5	51	0.5	23	0.5	18	0.5	16	0.5	15	0.5	17	
	Propagation			-40°C to 125°C	0.5	122	0.5	76	0.5	51	0.5	23	0.5	18	0.5	16	0.5	15	0.5	17	ns
'pd	delay	D	^	-40°C to 85°C	0.5	84	0.5	63	0.5	51	0.5	39	0.5	28	0.5	24	0.5	21	0.5	21	115
			A	-40°C to 125°C	0.5	84	0.5	63	0.5	51	0.5	39	0.5	28	0.5	24	0.5	21	0.5	21	
		DIB	Α	-40°C to 85°C	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	
.	Disable time	DIIX	^	-40°C to 125°C	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	ns
dis	Disable tille	DID	В	-40°C to 85°C	0.5	133	0.5	94	0.5	73	0.5	30	0.5	23	0.5	22	0.5	20	0.5	22	115
		DIIX	Ь	-40°C to 125°C	0.5	133	0.5	94	0.5	73	0.5	31	0.5	24	0.5	22	0.5	20	0.5	23	
		DIR	Α	-40°C to 85°C	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	
t _{en}	Enable time	DIK	A	-40°C to 125°C	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	
(1)	·	DIR	В	-40°C to 85°C	0.5	192	0.5	146	0.5	120	0.5	93	0.5	88	0.5	86	0.5	85	0.5	87	ns
		אוע	٥	-40°C to 125°C	0.5	192	0.5	146	0.5	120	0.5	93	0.5	88	0.5	86	0.5	85	0.5	87	

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.9 Switching Characteristics, $V_{CCA} = 1.2 \pm 0.1V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

t _{pd} Pro										ı	B-Port S	Supply	Voltage	(V _{CCB})								
	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ± (0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT	
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
		Α	В	-40°C to 85°C	0.5	84	0.5	51	0.5	38	0.5	15	0.5	10	0.5	9	0.5	7	0.5	8		
	Propagation	A	В	-40°C to 125°C	0.5	84	0.5	51	0.5	38	0.5	15	0.5	11	0.5	9	0.5	8	0.5	8	no	
Lpd	delay	В	Α	-40°C to 85°C	0.5	50	0.5	33	0.5	23	0.5	15	0.5	12	0.5	10	0.5	8	0.5	7	ns	
			^	-40°C to 125°C	0.5	50	0.5	33	0.5	23	0.5	15	0.5	12	0.5	10	0.5	8	0.5	7		
		DIR	Α	-40°C to 85°C	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26		
	Disable time	DIK	A	-40°C to 125°C	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	no	
^L dis	Disable time	DIR	В	-40°C to 85°C	0.5	129	0.5	90	0.5	70	0.5	27	0.5	20	0.5	18	0.5	15	0.5	15	ns	
		DIK		-40°C to 125°C	0.5	129	0.5	90	0.5	71	0.5	28	0.5	21	0.5	19	0.5	16	0.5	16		
		DIB	_	-40°C to 85°C	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177		
t _{en}		DIK	DIR A	-40°C to 125°C	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	no	
(1)		DIR B	DIR I	ь	-40°C to 85°C	0.5	105	0.5	71	0.5	59	0.5	40	0.5	36	0.5	35	0.5	33	0.5	34	ns
		אוט	B	-40°C to 125°C	0.5	105	0.5	71	0.5	59	0.5	41	0.5	37	0.5	36	0.5	34	0.5	35		

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.10 Switching Characteristics, $V_{CCA} = 1.5 \pm 0.1V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

	-									ı	B-Port S	Supply	Voltage	(V _{CCB})											
F	PARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT				
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX					
		Α	В	-40°C to 85°C	0.5	79	0.5	41	0.5	28	0.5	12	0.5	9	0.5	7	0.5	6	0.5	6					
	Propagation	A	В	-40°C to 125°C	0.5	79	0.5	41	0.5	28	0.5	12	0.5	9	0.5	8	0.5	6	0.5	6					
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	50	0.5	28	0.5	18	0.5	10	0.5	9	0.5	8	0.5	6	0.5	5	ns				
				-40°C to 125°C	0.5	50	0.5	28	0.5	18	0.5	11	0.5	9	0.5	8	0.5	6	0.5	5	[]				
	DIR	DIB	Α	-40°C to 85°C	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18					
	Disable time	DIK	A	-40°C to 125°C	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	no				
t _{dis}	Disable time		-40°C to 85°C	0.5	128	0.5	89	0.5	69	0.5	26	0.5	19	0.5	17	0.5	13	0.5	13	ns					
		DIR	DIR	DIR	DIR	DIR		-40°C to 125°C	0.5	128	0.5	89	0.5	70	0.5	27	0.5	20	0.5	18	0.5	14	0.5	14	[]
		DID	DIR A			DID A	-40°C to 85°C	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172		
t _{en}	En abla dina	DIK	A	-40°C to 125°C	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	no				
(1)	Enable time	DIR	В	-40°C to 85°C	0.5	92	0.5	54	0.5	42	0.5	31	0.5	27	0.5	25	0.5	24	0.5	24	ns				
		אוע		-40°C to 125°C	0.5	92	0.5	54	0.5	42	0.5	31	0.5	28	0.5	26	0.5	25	0.5	25					

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.11 Switching Characteristics, $V_{CCA} = 1.8 \pm 0.15V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										1	B-Port S	Supply '	Voltage	(V _{CCB})											
P.	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT				
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX					
		^	В	-40°C to 85°C	0.5	78	0.5	40	0.5	24	0.5	10	0.5	8	0.5	7	0.5	5	0.5	5					
	Propagation	A	В	-40°C to 125°C	0.5	78	0.5	40	0.5	24	0.5	10	0.5	8	0.5	7	0.5	6	0.5	5	ns				
t _{pd}	delay	В	_	-40°C to 85°C	0.5	56	0.5	27	0.5	16	0.5	9	0.5	7	0.5	7	0.5	5	0.5	4	115				
		В	A	-40°C to 125°C	0.5	56	0.5	27	0.5	16	0.5	9	0.5	8	0.5	7	0.5	5	0.5	5					
	DIR	DIB	Α	-40°C to 85°C	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16					
	Disable time	DIK	A	-40°C to 125°C	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	ns				
t _{dis}	Disable time	DID	В	-40°C to 85°C	0.5	127	0.5	88	0.5	69	0.5	25	0.5	18	0.5	16	0.5	12	0.5	12	115				
		DIR	DIR	DIR	DIR	В	-40°C to 125°C	0.5	127	0.5	88	0.5	70	0.5	26	0.5	19	0.5	17	0.5	13	0.5	13		
			DIR A	DIR A				-40°C to 85°C	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	
t _{en}					-40°C to 125°C	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	no			
(1)	Enable time	DIB	В	-40°C to 85°C	0.5	89	0.5	50	0.5	36	0.5	26	0.5	23	0.5	22	0.5	21	0.5	20	ns				
		DIR	DIR	B	-40°C to 125°C	0.5	89	0.5	50	0.5	36	0.5	27	0.5	24	0.5	23	0.5	22	0.5	21				

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.12 Switching Characteristics, $V_{CCA} = 2.5 \pm 0.2V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

											B-Port S	Supply	Voltage	(V _{CCB})											
	PARAMETER	FROM	то	Test Conditions	0.7 ± 0).05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT				
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX					
		Α	В	-40°C to 85°C	0.5	77	0.5	38	0.5	21	0.5	8	0.5	6	0.5	5	0.5	5	0.5	4					
	Propagation			-40°C to 125°C	0.5	77	0.5	38	0.5	21	0.5	8	0.5	6	0.5	5	0.5	5	0.5	5	ne				
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	71	0.5	28	0.5	15	0.5	7	0.5	6	0.5	5	0.5	5	0.5	4	ns				
			^	-40°C to 125°C	0.5	71	0.5	28	0.5	15	0.5	8	0.5	6	0.5	6	0.5	5	0.5	4					
	DIR Disable time	DID	Α	-40°C to 85°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11					
t _{dis}		DIK	^	-40°C to 125°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	ns				
^L dis	Disable time	DIB	В	-40°C to 85°C	0.5	127	0.5	88	0.5	68	0.5	25	0.5	18	0.5	15	0.5	12	0.5	11] 115				
		DIR	DIR	DIR	DIR	DIR		-40°C to 125°C	0.5	127	0.5	88	0.5	69	0.5	26	0.5	19	0.5	16	0.5	12	0.5	12	
		DID	٨	-40°C to 85°C	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182					
t _{en}		DIK	DIR A	-40°C to 125°C	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	no				
(1)	Enable time	DIR	В	-40°C to 85°C	0.5	84	0.5	46	0.5	29	0.5	18	0.5	17	0.5	16	0.5	15	0.5	15	ns				
		חות	B	-40°C to 125°C	0.5	84	0.5	46	0.5	29	0.5	19	0.5	18	0.5	17	0.5	16	0.5	16					

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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5.13 Switching Characteristics, $V_{CCA} = 3.3 \pm 0.3V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

	-										B-Port S	upply	Voltage	(V _{CCB})											
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT				
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX					
		Α	В	-40°C to 85°C	0.5	76	0.5	38	0.5	21	0.5	7	0.5	5	0.5	4	0.5	4	0.5	4					
	Propagation	A	В	-40°C to 125°C	0.5	76	0.5	38	0.5	21	0.5	7	0.5	5	0.5	5	0.5	4	0.5	4	no				
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	105	0.5	34	0.5	17	0.5	8	0.5	6	0.5	5	0.5	4	0.5	4	ns				
			^	-40°C to 125°C	0.5	105	0.5	34	0.5	17	0.5	8	0.5	6	0.5	5	0.5	5	0.5	4					
	DIR Disable time	_	-40°C to 85°C	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10						
		DIR	DIR A	JIK A	-40°C to 125°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	no			
t _{dis}	Disable time	DID	B	-40°C to 85°C	0.5	128	0.5	88	0.5	68	0.5	24	0.5	17	0.5	15	0.5	11	0.5	11	ns				
		DIR	DIR B	DIR P	DIR	DIR		-40°C to 125°C	0.5	128	0.5	88	0.5	69	0.5	26	0.5	19	0.5	16	0.5	12	0.5	11	
		DIR A			A	-40°C to 85°C	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218			
t _{en}		DIK	A	-40°C to 125°C	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218					
(1)	Enable time	DIB	В	-40°C to 85°C	0.5	83	0.5	45	0.5	28	0.5	17	0.5	15	0.5	14	0.5	14	0.5	14	ns				
		DIR	5	-40°C to 125°C	0.5	83	0.5	45	0.5	28	0.5	18	0.5	16	0.5	15	0.5	15	0.5	15					

⁽¹⁾ The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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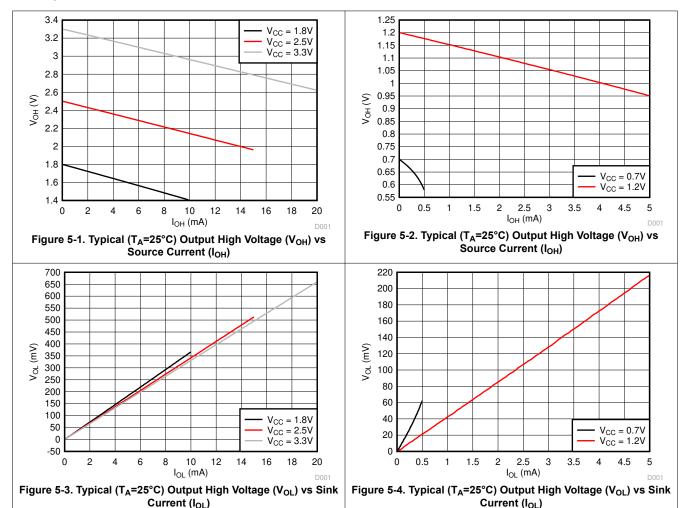
5.14 Operating Characteristics: $T_A = 25$ °C

	PARAMETER	TEST CONDITIONS	V _{CCA}	V _{CCB}	MIN	TYP	MAX	UNIT	
			0.7V	0.7V		2.2			
			0.8V	0.8V		2.0			
			0.9V	0.9V		2.0			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		2.0		pF	
	per transceiver (A to B)	1MHz, tr = tf = 1 ns	1.5V	1.5V		2.0		рг	
			1.8V	1.8V		2.1			
			2.5V	2.5V		2.5			
			3.3V	3.3V		3.0			
C _{pdA}			0.7V	0.7V		10.6			
			0.8V	V8.0		10.7			
			0.9V	0.9V		10.6			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		10.8		nE	
	per transceiver (B to A)	1MHz, tr = tf = 1 ns	1.5V	1.5V		11.1		pF	
			1.8V	1.8V		12.2			
			2.5V	2.5V		15.9			
			3.3V	3.3V		19.6			
			0.7V	0.7V		10.6			
			0.8V	V8.0		10.7			
			0.9V	0.9V		10.6			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		10.8		nE	
	per transceiver (A to B)	1MHz, tr = tf = 1 ns	1.5V	1.5V		11.1		pF	
			1.8V	1.8V		12.2			
			2.5V	2.5V		15.8			
C			3.3V	3.3V		19.3			
C _{pdB}			0.7V	0.7V		2.2			
			0.8V	0.8V		2.0			
			0.9V	0.9V		2.0			
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		2.0		pF	
	per transceiver (B to A)	1MHz, tr = tf = 1 ns	1.5V	1.5V		2.0		ρı	
			1.8V	1.8V		2.1			
		2.5V 2.5V 2.5							
			3.3V	3.3V		3.0			

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5.15 Typical Characteristics



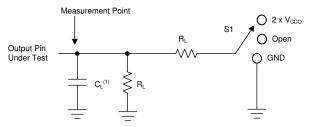


6 Parameter Measurement Information

6.1 Load Circuit and Voltage Waveforms

Unless otherwise noted, all input pulses are supplied by generators having the following characteristics:

- f = 1MHz
- $Z_O = 50\Omega$
- dv/dt ≤ 1 ns/V

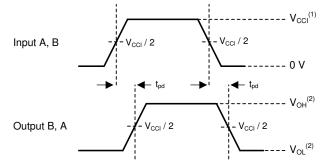


A. C_L includes probe and jig capacitance.

Figure 6-1. Load Circuit

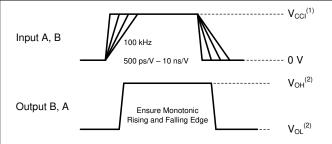
Table 6-1. Load Circuit Conditions

	Parameter	V _{cco}	R _L	CL	S ₁	V _{TP}
Δt/Δν	Input transition rise or fall rate	0.65V - 3.6V	1ΜΩ	15pF	Open	N/A
	Propagation (delay) time	1.1V – 3.6V	2kΩ	15pF	Open	N/A
t _{pd}	Propagation (delay) time	0.65V - 0.95V	20kΩ	15pF	Open	N/A
		3V – 3.6V	2kΩ	15pF	2 × V _{CCO}	0.3V
	Enable time disable time	1.65V – 2.7V	2kΩ	15pF	2 × V _{CCO}	0.15V
len, ldis	Enable time, disable time	1.1V – 1.6V	2kΩ	15pF	2 × V _{CCO}	0.1V
		0.65V - 0.95V	20kΩ	15pF	2 × V _{CCO}	0.1V
		3V – 3.6V	2kΩ	15pF	GND	0.3V
		1.65V – 2.7V	2kΩ	15pF	GND	0.15V
len, ldis	Enable time, disable time	1.1V – 1.6V	2kΩ	15pF	GND	0.1V
		0.65V - 0.95V	20kΩ	15pF	GND	0.1V



- 1. V_{CCI} is the supply pin associated with the input port.
- V_{OH} and V_{OL} are typical output voltage levels that occur with specified R_L, C_L, and S₁

Figure 6-2. Propagation Delay



- 1. V_{CCI} is the supply pin associated with the input port.
- 2. V_{OH} and V_{OL} are typical output voltage levels that occur with specified R_L , C_L , and S_1

Figure 6-3. Input Transition Rise or Fall Rate

----- GND

DIR $V_{CCA}/2$ $V_{CCA}/2$ $V_{CCA}/2$ $V_{CCA}/2$ $V_{CCO}/2$ $V_{CCO}/2$

- A. Illustrative purposes only. Enable Time is a calculation as described in the Application Information section.
- B. Output waveform on the condition that input is driven to a valid Logic Low.
- C. Output waveform on the condition that input is driven to a valid Logic High.
- D. V_{CCI} is the supply pin associated with the input port.
- E. V_{CCO} is the supply pin associated with the output port.
- F. V_{OH} and V_{OL} are typical output voltage levels with specified R_L , C_L , and S_1 .

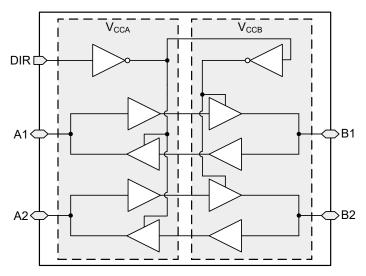
Figure 6-4. Enable Time And Disable Time

7 Detailed Description

7.1 Overview

The SN74AXC2T45-Q1 is a 2-bit, dual-supply non-inverting bidirectional voltage level translation device. Ax pins and the DIR pin are referenced to V_{CCA} logic levels, and Bx pins are referenced to V_{CCB} logic levels. The A port is able to accept I/O voltages ranging from 0.65V to 3.6V, while the B port can accept I/O voltages from 0.65V to 3.6V. A high on DIR enables data transmission from A to B and a low on DIR enables data transmission from B to A. See Section 7.4 for a summary of the operation of the control logic.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Standard CMOS Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in Section 5.5. The worst case resistance is calculated with the maximum input voltage, given in Section 5.1, and the maximum input leakage current, given in the Section 5.5, using Ohm's law ($R = V \div I$).

Signals applied to the inputs need to have fast edge rates, as defined by $\Delta t/\Delta v$ in Section 5.3 to avoid excessive current consumption and oscillations. If a slow or noisy input signal is required, a device with a Schmitt-trigger input should be used to condition the input signal prior to the standard CMOS input.

7.3.2 Balanced High-Drive CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The high drive capability of this device creates fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. The electrical and thermal limits defined in Section 5.1 must be followed at all times.

7.3.3 Partial Power Down (Ioff)

The inputs and outputs for this device enter a high-impedance state when the device is powered down, inhibiting current backflow into the device. The maximum leakage into or out of any input or output pin on the device is specified by I_{off} in Section 5.5.

7.3.4 V_{CC} Isolation

The inputs and outputs for this device enter a high-impedance state when either supply is <100mV.

7.3.5 Over-voltage Tolerant Inputs

Input signals to this device can be driven above the supply voltage so long as they remain below the maximum input voltage value specified in Section 5.3.

Product Folder Links: SN74AXC2T45-Q1

7.3.6 Glitch-Free Power Supply Sequencing

Either supply rail may be powered on or off in any order without producing a glitch on the I/Os (that is, where the output erroneously transitions to V_{CC} when it should be held low). Glitches of this nature can be misinterpreted by a peripheral as a valid data bit, which could trigger a false device reset of the peripheral, a false device configuration of the peripheral, or even a false data initialization by the peripheral. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report.

7.3.7 Negative Clamping Diodes

The inputs and outputs to this device have negative clamping diodes as depicted in Figure 7-1.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input negative voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

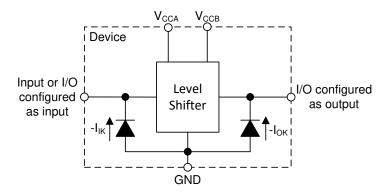


Figure 7-1. Electrical Placement of Clamping Diodes for Each Input and Output

7.3.8 Fully Configurable Dual-Rail Design

Both the V_{CCA} and V_{CCB} pins can be supplied at any voltage from 0.65V to 3.6V, making the device suitable for translating between any of the voltage nodes (0.7V, 0.8V, 0.9V, 1.2V, 1.8V, 2.5V, and 3.3V).

7.3.9 I/Os with Integrated Static Pull-Down Resistors

To help avoid floating inputs on the I/Os, this device has $71k\Omega$ typical integrated weak pull-downs on all data I/Os. This feature allows all inputs to be left floating without the concern for unstable outputs or increased current consumption. This also helps to reduce external component count for applications where not all channels are used or need to be fixed low. If an external pull-up is required, it should be no larger than $7k\Omega$ to avoid contention with the $71k\Omega$ internal pull-down.

7.3.10 Supports High-Speed Translation

The SN74AXC2T45-Q1 device can support high data-rate applications. The translated signal data rate can be up to 380Mbps when the signal is translated from 1.8V to 3.3V.

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7.4 Device Functional Modes

Table 7-1. Function Table⁽¹⁾

CONTROL INPUT	Port Status		OPERATION
DIR	A PORT	B PORT	OPERATION
L	Output (Enabled)	Input (Hi-Z)	B data to A bus
Н	Input (Hi-Z)	Output (Enabled)	A data to B bus

(1) Input circuits of the data I/O's are always active.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The SN74AXC2T45-Q1 device can be used in level-translation applications for interfacing devices or systems operating at different interface voltages with one another. The SN74AXC2T45-Q1 device is ideal for use in applications where a push-pull driver is connected to the data I/Os. The maximum data rate can be up to 380Mbps when device translates a signal from 1.8V to 3.3V.

Figure 8-1 shows one example application where the SN74AXC2T45-Q1 device is used to translate low voltage error signals from a CPU to a higher voltage signal to properly drive the inputs of a system controller, thus alerting the system of any CPU errors such as overheating or other catastrophic processor errors.

8.1.1 Enable Times

Calculate the enable times for the SN74AXC2T45-Q1 using the following formulas:

$$t_{A_en}$$
 (DIR to A) = t_{dis} (DIR to B) + t_{pd} (B to A) (1)

$$t_{B en}$$
 (DIR to A) = t_{dis} (DIR to A) + t_{pd} (A to B) (2)

In a bidirectional application, these enable times provide the maximum delay time from the time the DIR bit is switched until an output is expected. For example, if the SN74AXC2T45-Q1 initially is transmitting from A to B, then the DIR bit is switched; the B port of the device must be disabled (t_{dis}) before presenting it with an input. After the B port has been disabled, an input signal applied to it appears on the corresponding A port after the specified propagation delay (t_{pd}) . To avoid bus contention care should be taken to not apply an input signal prior to the output port being disabled (t_{dis}) maximum.

8.2 Typical Application

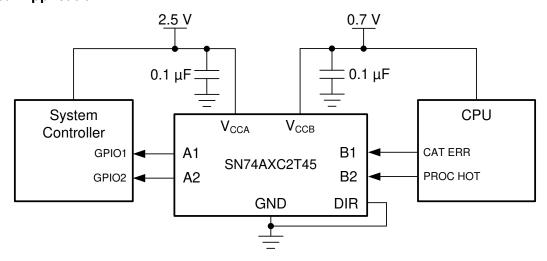


Figure 8-1. Processor Error Application



8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1.

Table 8-1. Design Parameters

DESIGN PARAMETERS	EXAMPLE VALUES
Input voltage range	0.65V to 3.6V
Output voltage range	0.65V to 3.6V

8.2.2 Detailed Design Procedure

To begin the design process, determine the following:

- · Input voltage range
 - Use the supply voltage of the device that is driving the SN74AXC2T45-Q1 device to determine the input voltage range. For a valid logic-high, the value must exceed the high-level input voltage (V_{IH}) of the input port. For a valid logic low the value must be less than the low-level input voltage (V_{IL}) of the input port.
- Output voltage range
 - Use the supply voltage of the device that the SN74AXC2T45-Q1 device is driving to determine the output voltage range.

8.2.3 Application Curve

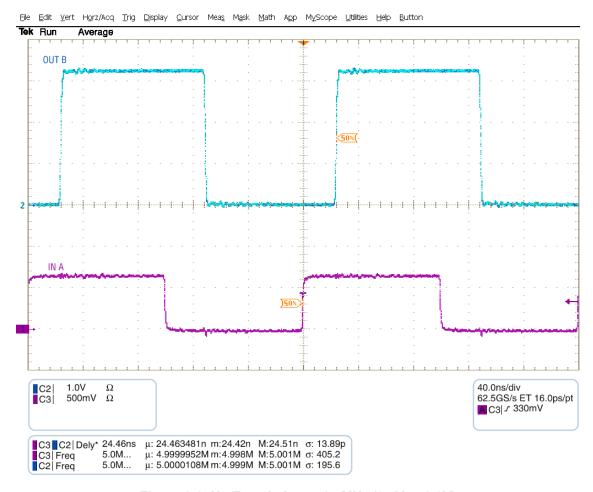


Figure 8-2. Up Translation at 2.5MHz (0.7V to 3.3V)

Product Folder Links: SN74AXC2T45-Q1



8.3 Power Supply Recommendations

Always apply a ground reference to the GND pins first. This device is designed for glitch free power sequencing without any supply sequencing requirements such as ramp order or ramp rate.

This device is designed with various power supply sequencing methods in mind to help prevent unintended triggering of downstream devices. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report.

8.4 Layout

8.4.1 Layout Guidelines

For device reliability, following common printed-circuit board layout guidelines are recommended:

- Use bypass capacitors on the power supply pins and place them as close to the device as possible. A
 0.1μF capacitor is recommended, but transient performance can be improved by having both 1μF and 0.1μF
 capacitors in parallel as bypass capacitors.
- · Use short trace lengths to avoid excessive loading.

8.4.2 Layout Example

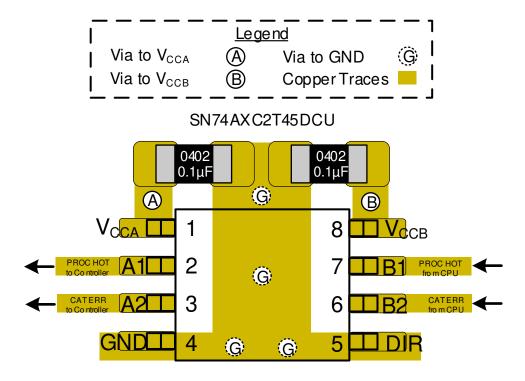


Figure 8-3. SN74AXC2T45DTM Layout Example



9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Implications of Slow or Floating CMOS Inputs application report
- Texas Instruments, Power Sequencing for AXC Family of Devices application report

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Trademarks

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

11 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (September 2021) to Revision B (January 2024)	Page
Added the I/Os with Integrated Static Pull-Down Resistors section	18
Changes from Revision * (April 2021) to Revision A (September 2021)	Page
Changed the status of the data sheet from: Advance Information to: Production Data	1

Product Folder Links: SN74AXC2T45-Q1



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74AXC2T45QDCURQ1	ACTIVE	VSSOP	DCU	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2FZT	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF SN74AXC2T45-Q1:

PACKAGE OPTION ADDENDUM

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● Catalog : SN74AXC2T45

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

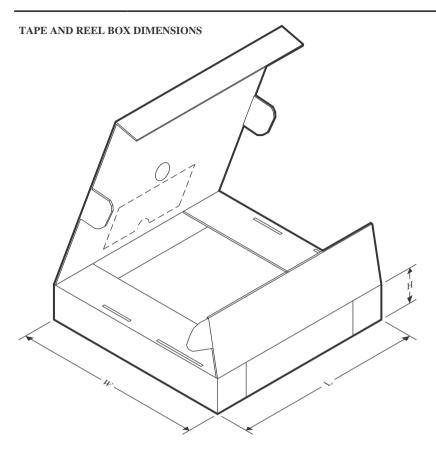


*All dimensions are nominal

Device	U	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AXC2T45QDCURQ1	VSSOP	DCU	8	3000	178.0	9.0	2.25	3.35	1.05	4.0	8.0	Q3

PACKAGE MATERIALS INFORMATION

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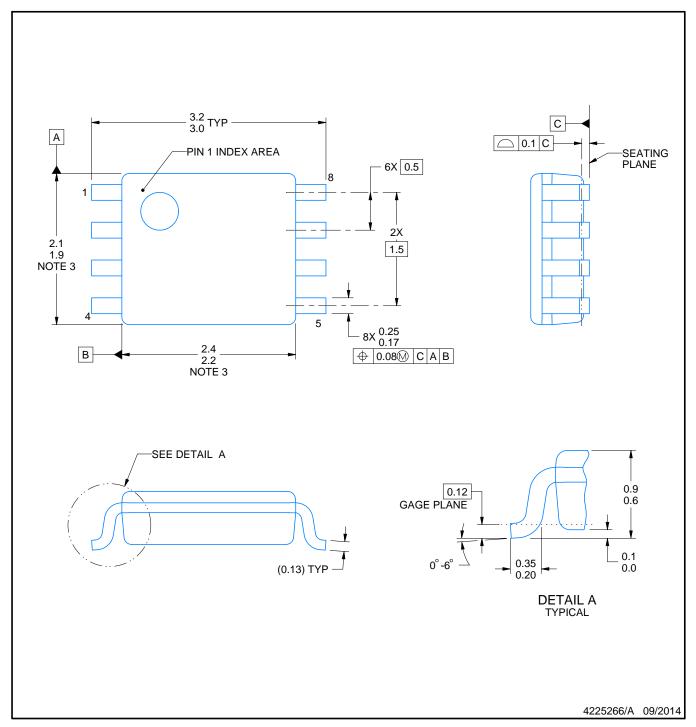


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AXC2T45QDCURQ1	VSSOP	DCU	8	3000	180.0	180.0	18.0



SMALL OUTLINE PACKAGE



NOTES:

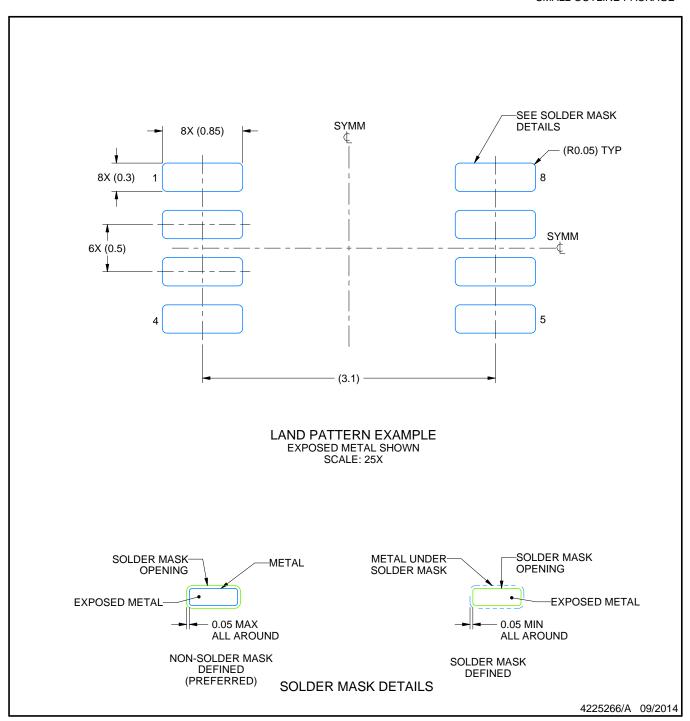
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-187 variation CA.



SMALL OUTLINE PACKAGE

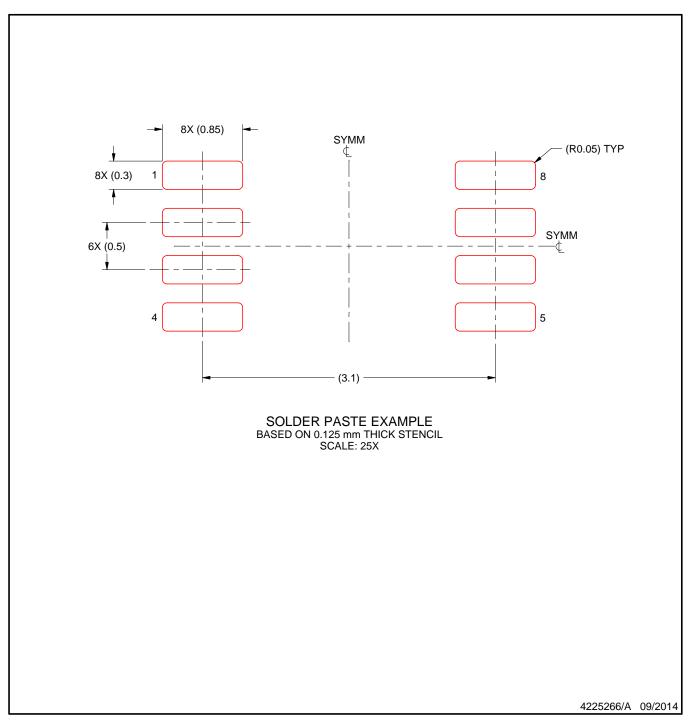


NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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